

FORM PTO-1449		U. S DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.	SERIAL NO.
				U 013711-6	10/009,884
				APPLICANT	
				Hiroyuki ONISHI, et al.	
				FILING DATE	GROUP
				November 13, 2001	1746
U. S. PATENT DOCUMENTS					
EXAMINER INITIALS	DESIGNATION	DOCUMENT NUMBER	DATE	NAME	FILING DATE IF APPROPRIATE
<i>WPF</i>	AA	6,130,024	10/2000	Aylward et al.	
<i>WPF</i>	AB	4,741,969	05/1988	Hayama et al.	
FOREIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION
					YES
<i>WPF</i>	AC	0 995 609	04/2000	EP	X
	AD	1 291990	11/1989	JP	X
	AE	0 703 087	03/1996	EP	
	AF	11 279441	10/1999	JP	
	AG	0 406 761	01/1991	EP	
	AH	7 041 726	02/1995	JP	
	AI	11 263052	09/1999	JP	
<i>V</i>	AJ	8 174989	07/1996	JP	
OTHER ART (Including Author, Title, Date, Pertinent Dates, Etc.)					
<i>WPF</i>	AK	Patent Abstracts of Japan of JP 1 291990 dated November 24, 1989			
	AL				
	AM				
	AN				
	AO				
	AP				
EXAMINER	<i>John D. Mulligan</i>		DATE CONSIDERED <i>2/28/2005</i>		
EXAMINER:	Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.				

U. S DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.	SERIAL NO.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		U 013711-6	10/009,884
(Use several sheets if necessary)		APPLICANT	
		ONISHI ET AL.	
		FILING DATE	GROUP
		NOVEMBER 13, 2001	

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	REFERENCE DESIGNATION	DOCUMENT NUMBER	DATE	NAME	FILING DATE IF APPROPRIATE
	AA				
	AB				
	AC				
	AD				
	AE				
	AF				
	AG				
	AH				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
WPF	AL	08 104000	04/1996	JP		X
↓	AM	08 072230	03/1996	JP		X
↓	AN	08 216434	08/1996	JP		X
↓	AO	08 216392	08/1996	JP		X
	AP					

OTHER ART (Including Author, Title, Date, Pertinent Dates, Etc.)

WPF	AR	Patent Abstracts of Japan of JP 08-104000 dated April 23, 1996
↓	AS	Patent Abstracts of Japan of JP 08-072230 dated March 19, 1996
↓		Patent Abstracts of Japan of JP 08-216434 dated August 27, 1996
↓	AT	Patent Abstracts of Japan of JP 08-216392 dated August 27, 1996

EXAMINER	<i>Dan Phillips Hatch</i>	DATE CONSIDERED	2/28/2006
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